

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Tetsuo NAGANO et al.

Group Art Unit: 1797

Appln. No. : 10/531,664

(U.S. National Phase of PCT/JP2003/013179)

Examiner: Fritchman

I.A. Filed : October 15, 2003

Conf. No: 1923

For : REAGENTS FOR THE MEASUREMENT OF PEROXYNITRITES

**SUPPLEMENTAL AMENDMENT UNDER 37 C.F.R. 41.33  
IN RESPONSE TO FINAL OFFICE ACTION DATED MAY 14, 2009**

Commissioner for Patents  
U.S. Patent and Trademark Office  
Customer Service Window, Mail Stop AF  
Randolph Building  
401 Dulany Street  
Alexandria VA 22314

Sir:

This is in response to the Final Office Action from the U.S. Patent and Trademark Office dated May 14, 2009, which sets a three month shortened statutory period for response until August 14, 2009.

Applicants have filed a Notice of Appeal on November 16, 2009 (November 14, 2009 being a Saturday) so that the time for filing an Appeal Brief extends until January 16, 2010.

Applicants hereby request an extension of time for one month to extend the period for response until February 16, 2010, and are concurrently filing a formal Request for Extension of Time for one month accompanied by the government fee. If for any reason the Request for Extension of Time is not associated with the file at the Patent and Trademark Office and/or if the fee is deficient and/or any extensions of time are necessary, such as any necessary extension of time for entry of an Examiner's Amendment, this is an express request for any required

extension of time to maintain the pendency of the application, and authorization to charge any required extension of time fee and/or any other fee necessary to maintain pendency of the application, including any necessary claim fee, to Deposit Account No. 19-0089.

**Amendments to the Claims** begin on page 3 of this paper.

**Remarks** begin on page 5 of this paper.

Applicants note that an Appeal Brief is being prepared for filing.

Reconsideration and withdrawal of the rejections of record are respectfully requested in view of the remarks presented herein.